Am25LS2536

Eight-Bit Decoder with Control Storage

DISTINCTIVE CHARACTERISTICS

- 8-bit decoder/demultiplexer with control storage
- 3-state outputs
- Common clock enable

- Common clear
- Polarity control
- Advanced Low-Power Schottky Process

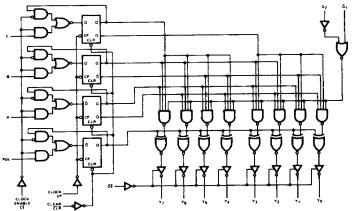
GENERAL DESCRIPTION

The Am25LS2536 is an eight-bit decoder with control storage. It provides a conventional 8-bit decoder function with two enable inputs which may also be used for data input. This can be used to implement a demultiplexer function. In addition, the exclusive "OR" gate allows for polarity control of the selected output. The 3-state outputs are enabled by a LOW on the (OE) output enable.

The three control bits representing the output selection and the single bit polarity control are stored in "D" type flip-flops. These flip-flops have both Clear, Clock, and Clock Enable functions provided. The \overline{G}_1 and G_2 input provide either polarity for input control or data.

BLOCK DIAGRAM

8-Bit Decoder/Demultiplexer with Control Storage



BD001630

RELATED PRODUCTS

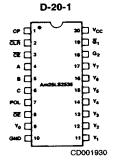
Part No.	Description					
Am25LS2537	1 of 10 Decoder					
Am25LS2538	1 of 8 Decoder					
Am25LS2539	Dual 1 of 4 Decoder					
Am25LS2548	Chip Select Address Decoder					
Am2921	1 of 8 Decoder					
Am2924	3 to 8 Line Decoder/Demultiplexer					

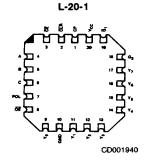
03666B

9-120 R

Refer to Page 13-1 for Essential Information on Military Devices

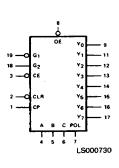
CONNECTION DIAGRAM Top View

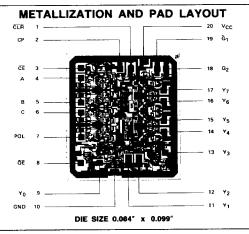




Note: Pin 1 is marked for orientation

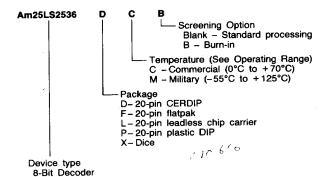
LOGIC SYMBOL





ORDERING INFORMATION

AMD products are available in several packages and operating ranges. The order number is formed by a combination of the following: Device number, speed option (if applicable), package type, operating range and screening option (if desired).



Valid Cor	nbinations
Am25LS2536	PC DC, DM FM LC, LM XC, XM

Valid Combinations

Consult the AMD sales office in your area to determine if a device is currently available in the combination you wish.

03666B

9-121

PIN DESCRIPTION

Pin No.	Name	1/0	Description
2	CLR		Clear. When the CLEAR input is LOW, the control register outputs (Q _A , Q _B , Q _C , Q _{POL}) are set LOW regardless of any other inputs.
1	CP	1	Clock. Enters data into the control register on the LOW-to-HIGH transition.
3	CE		Clock Enable. Allows data to enter the control register when \overline{CE} is LOW. When \overline{CE} is HIGH, the Q_i outputs do not change state, regardless of data or clock input transitions.
4, 5, 6	A, B, C	1 1	Inputs to the control register which are entered on the LOW-to-HIGH clock transition if CE is LOW.
7	POL	1 1	Input to the control register bit used for determining the polarity of the selected output.
19	G₁	ı	Active LOW part of the expression $G = \overline{G}_1 \oplus G_2$ where G is either data input for the selected Y_n or is used as an input enable.
18	G ₂	$\pm \tau$	Active HIGH part of the expression G = \overline{G}_1G_2 .
	Yn	0	The three-state outputs. When active (\overline{OE} = LOW), one of eight outputs is selected by the code stored in the control register, with the polarity of all eight determined by the bit stored in the POL flip-flop of the control register. The selected output can further be controlled by G according to the expression YSELECTED = $\overline{G} \oplus \overline{OPOL}$.
8	ŌĒ		Output Enable. When \overline{OE} is HIGH the Y_n outputs are in the high impedance state; when \overline{OE} is LOW the Y_n 's are in their active state as determined by the other control logic. The \overline{OE} input affects the Y_n output buffers only and has no effect on the control register or any other logic.

FUNCTION TABLE

				h	nput	8					Inte Regi	rnal sters	•			Thre	e-Sta	te O	utput	8	
Mode	С	В	A	POL	CE	CLR	G*	ŌĒ	СР	Qc	αв	QA	Q _{POL}	Yo	Υ1	Y ₂	Υ3	Y4	Y5	Y ₆	Y7
Clear	X	X X	×	×	X	L	L H	L	X	L	L	L L	L	H L	H	Н	H	H	H	H	Н
Hold	Х	×	×	Х	н	Н	NC	L	1	NC	NC	NC	NC	NC	NC	NC	NC	NC	NC	NC	NC
Select				######################################					t				H # # # # # # L L L L L L L L L L L L L								
Output Disable	×	×	×	х	х	х	Х	н	Х	NC	NC	NC	NC	z	z	Z	z	z	Z	Z	Z

NC = No Change X = Don't Care Z = High-Impedance $\uparrow = Low-to-High$ Transition

	G ₁	G ₂	G
ſ	L	L	L
1	L	н	Н
١	H	L	L
l	Н	н	L

ABSOLUTE MAXIMUM RATINGS Storage Temperature-65°C to +150°C Ambient Temperature Under Bias -55°C to +125°C Supply Voltage to Ground Potential Continuous-0.5V to +7.0V DC Voltage Applied to Outputs For High Output State-0.5V to +V_{CC} max DC Input Voltage.....-0.5V to +7.0V DC Output Current, Into Outputs 30mA

Stresses above those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

DC Input Current-30mA to +5.0mA

OPERATING RANGES

Commercial (C) Devices	
Temperature	0°C to +70°C
Supply Voltage	+ 4.75V to + 5.25V
Military (M) Devices	
Temperature	55°C to +125°C
Supply Voltage	+ 4.5V to + 5.5V
Operating ranges define those limits	over which the function-
ality of the device is guaranteed.	

DC CHARACTERISTICS over operating range unless otherwise specified

Parameters	Description	Test Co	enditions (N	ote 2)	Min	Typ (Note 1)	Max	Units	
			V _{CC} = MIN I _{OH} = -2.6mA			3.2			
VOH	Output HIGH Voltage	VIN = VIH or VIL	I _{OH} = -1.0mA, MIL.		2.4	3.4		Volts	
		V _{CC} = MIN	I _{OL} = 24	nA, COM'L		0.4	0.5		
VOL	Output LOW Voltage	VIN = VIH or VIL				0.35	0.4	Volts	
VIH	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs			2.0			Volts	
		Guaranteed input logical LOW		MIL			0.7		
V _{IL} Input LOW Level	voltage for all inputs. COM'L					0.8	Volts		
VI	Input Clamp Voltage	V _{CC} = MIN, I _{IN} = -18mA					-1.5	Volts	
.liL	Input LOW Current	VCC = MAX, VIN =	0.4V				-0.4	mA	
Лн	Input HIGH Current	V _{CC} = MAX, V _{IN} =	2.7V				20	μΑ	
l _l	Input HIGH Current	V _{CC} = MAX, V _{IN} =	- 7.0V				0.1	mA	
·	Off-State (High-Impedance)		V _O = 0.4	V			-20		
10	Output Current	V _{CC} = MAX	V _O = 2.4	V			20	μΑ	
Isc	Output Short Circuit Current (Note 3)	V _{CC} = MAX					-85	mA	
lcc	Power Supply Current (Note 4)	V _{CC} = MAX				37	56	mA	

Notes: 1. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.

2. For conditions shown as MIN or MAX, use the appropriate value specified under Operating Ranges for the applicable device type.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. Test Conditions A = B = C = G₁ = OE = CE = GND; CLK = CLR = POL = G₂ = 4.5V.

SWITCHING CHARACTERISTICS ($T_A = +25^{\circ}C$, $V_{CC} = 5.0V$)

Parameters	Description		Test Conditions	Min	Тур	Max	Units	
		·			17	25		
tPLH	G₁ to Y₀ - Y7				23	34	ns	
tplH		-			20	30		
tpLH	G ₂ to Y ₀ - Y ₇				26	39	ns	
tphL			†		24	36		
tPLH	CP to Y0 - Y7		C _L = 45pF		30	45	ns	
t _{PHL}			R _L = 667Ω		24	36		
tplH	CLR to Y ₀ - Y ₇			"	31	46		
t _{PHL}				25			ns	
t _B	Clock Enable to C	P		0				
t _h				15			ns	
t _s	A, B, C, POL to C	P		0				
th .			C _L = 5pF		9	14		
t _{HZ}	ŌĒ to Y₀ - Y7		$R_L = 667\Omega$		11	17	ns ns	
t _{LZ}	 				15	22		
tzH	ŌĒ to Y0 - Y7		C _L = 45pF		16	24	ns ns	
tzL	Set-up Time, Clear Recovery to CP		$R_L = 667\Omega$	20			ns	
ts	Set-up Time, Clear	Clock		15	 		T -	
tpw	Pulse Width Clear		┧ Ի	15			ns	

SWITCHING CHARACTERISTICS over operating range unless otherwise specified*

				COMM	ERCIAL	MILIT	-		
				Am25	LS2536	Am25L			
Parameters	Descri	ption	Test Conditions	Min	Max	M!n	Max	Units	
PLH					29		31		
PHL	G1 to Y0 - Y7		_		39		42	ns	
					34		37		
PLH	G ₂ to Y ₀ - Y ₇				44		48	95 54 ns	
lphL lpLH	 		<u> </u>		40		42		
	CP to Y ₀ - Y ₇		C _L = 45pF R _L = 667Ω			51			
PHL						47			
PLH	CLA to Yo - Y7				58		66		
PHL				27		30			
s	Clock Enable to	CP		0		0		ns	
th	 			17		20		ns	
t _s	A, B, C, POL to	CP		0		0			
t _h			0 50=5		17		18		
t _{HZ}	OE to Yo - Y7		C _L = 5.0pF RL = 667Ω		27		34	ns	
tLZ					25		27		
tzH	OE to Yo - Y7		-		28		30	ns	
tzı		r Recovery to CP	C _L = 5.0pF	23		25		ns	
t _s	Set-up Time, Clea	Clock	R _L = 667Ω	17		20			
t _{pw}	Pulse Width	Clear	∤	15	†	15		ns	

^{*}AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.